WHAT IS CLAIMED IS:

1. An electrical component testing apparatus, comprising:

a vacuum plate including:

a first surface;

a second surface opposite the first surface; and

a plurality of through-holes extending through the vacuum plate from the first surface to the second surface;

a manifold arranged at the second surface of the vacuum plate, the manifold including:

a manifold body; and

a plurality of passageways extending within the manifold body, wherein each of the plurality of passageways includes a first end and a second end, wherein the first end of each of the plurality of passageways includes an opening that intersects an exterior of the manifold body at a first location corresponding to a location of a through-hole in the vacuum plate and wherein the second end of each of the plurality of passageways includes an opening that intersects an exterior of the manifold body at a second location; and

a source of pressurized air coupled to the opening of the second end.

2. The apparatus of claim 1, wherein at least one of the plurality of passageways has a length that is substantially equal to the length of at least one other of the plurality of passageways.

3. The apparatus of claim 1, wherein the manifold body is formed of a visually transparent material.

4. The apparatus of claim 1, wherein at least one selected from the group consisting of the first end of each of the plurality of passageways and the second end of each of the plurality of passageways further includes an annular channel formed in the exterior surface of the manifold body and extending around the opening.

5. The apparatus of claim 4, further comprising a seal arranged within the annular channel.

6. The apparatus of claim 1, further comprising a test plate arranged on the first surface of the vacuum plate, wherein the test plate includes a plurality of through-holes and wherein the test plate is moveable relative to the vacuum plate such that at least some of the plurality of through-holes in the test plate are alignable to the plurality of through-holes in the vacuum plate.

7. The apparatus of claim 6, wherein the test plate is configured to retain a plurality of electrical components.

8. The apparatus of claim 6, wherein the plurality of through-holes in the test plate are configured to retain a plurality of electrical components.

9. The apparatus of claim 8, wherein the electrical component is an MLCC chip.

10. The apparatus of claim 8, further comprising:

a plurality of tube assemblies each having a first end and a second end opposite the first end, wherein, for each of the plurality of tube assemblies, the second end is lower than the first end, wherein the first end of each of the plurality of tube assemblies is configured to receive at least some of the plurality of electrical components and each of the plurality of tube assemblies is configured such that received electrical components can travel therethrough along a path of travel; and

a decelerator body having a plurality of openings formed therein, wherein each of the plurality of openings is in fluid communication with a corresponding second end of each of the plurality of tube assemblies to receive electrical components traveling through the plurality of tube assemblies; and

a decelerator arranged within each of the plurality of openings, wherein the decelerator is configured to decelerate the electrical components received within a corresponding one of the plurality of openings.

11. The apparatus of claim 10, wherein the second end of each of the plurality of tube assemblies is inserted into a corresponding opening formed in the decelerator body.

12. The apparatus of claim 10, further comprising a bin arranged beneath a decelerator within at least one of the plurality of openings, wherein the bin is configured to receive electrical components discharged by the decelerator.

13. An electrical component testing apparatus, comprising:

a plurality of ejection tubes, wherein each ejection tube includes a first end and a second end opposite the first end, wherein the second end is lower than the first end, wherein the first end is configured to receive a plurality of electrical components and each ejection tube is configured such that received electrical components can travel therethrough along a path of travel;

a plurality of decelerators, wherein each decelerator comprises:

a decelerator body having a plurality of openings formed therein, wherein each of the plurality of openings is aligned with a corresponding second end of an ejection tube, each of the plurality of openings having a first end and a second end opposite the first end; and

a structure defining a convex surface formed within each of the plurality of openings and facing toward first end of each of the plurality of openings; and

a concave surface arranged below the structure.

14. The apparatus of claim 13, wherein the concave surface defines the second end of the opening.

15. The apparatus of claim 13, wherein the first end of the opening is larger than the second end.

16. The apparatus of claim 13, wherein the decelerator bodies of the plurality of decelerators are integrally formed with each other.

17. The apparatus of claim 2, wherein the length of each of the plurality of passageways is substantially the same.

18. The apparatus of claim 2, wherein the first ends of at least some of the plurality of passageways are arranged in a circular pattern.

19. The apparatus of claim 2, wherein the second ends of at least some of the plurality of passageways are arranged in a linear pattern.